



Form PT-149

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.  
M122-1550SERIAL NO.  
09/687,600

## LIST OF ART CITED BY APPLICANT

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APPLICANT  
Micron Technology, Inc.FILING DATE  
October 12, 2000GROUP  
3724

## U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
h	AA	4,807,504	2/28/89	Vandermarliere			
h	AB	4,822,015	4/18/89	Glasman et al.			
h	AC	5,063,800	11/12/91	Jung et al.			
h	AD	5,288,061	2/22/94	Pieroni			
h	AE	5,970,606	10/26/99	Buechele			
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

## FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1550	SERIAL NO. Filed Herewith	
<b>LIST OF ART CITED BY APPLICANT</b> (Use several sheets if necessary)				APPLICANT Jason E. Tripard		
				FILING DATE Filed Herewith		GROUP Unknown
U.S. PATENT DOCUMENTS						
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
W	AA	5,173,766	12/22/92	Long et al.	—	—
	AB					
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FOREIGN PATENT DOCUMENTS						
	Document Number	Date	Country	Class	Subclass	Translation
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)						
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